
**Nanotechnologies — Characterization
of single-wall carbon nanotubes using
ultraviolet-visible-near infrared (UV-
Vis-NIR) absorption spectroscopy**

*Nanotechnologies — Caractérisation des nanotubes à simple couche
de carbone par utilisation de la spectroscopie d'absorption UV-Vis-NIR*

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ISO copyright office
Ch. de Blandonnet 8 • CP 401
CH-1214 Vernier, Geneva, Switzerland
Tel. +41 22 749 01 11
Fax +41 22 749 09 47
copyright@iso.org
www.iso.org

Contents

Page

Foreword	iv
1 Scope	1
2 Normative references	1
3 Terms, definitions and abbreviated terms	1
3.1 Terms and definitions.....	1
3.2 Abbreviated terms	2
4 Principle	2
4.1 General.....	2
4.2 UV-Vis-NIR absorption spectroscopy	2
4.3 Optical absorption peaks of SWCNTs in the UV-Vis-NIR region.....	2
4.4 Relation between SWCNT diameter and optical absorption peaks.....	4
4.5 Derivation of the purity indicator from optical absorption peak areas.....	4
4.6 Derivation of ratio of metallic SWCNTs from optical absorption peak areas.....	6
5 UV-Vis-NIR spectrometer	6
6 Sample preparation method	6
6.1 General.....	6
6.2 Preparation of D ₂ O dispersion for measurement of mean diameter and the ratio of metallic SWCNTs.....	7
6.3 Preparation of solid film dispersion for measurement of the mean diameter and the ratio of metallic SWCNTs	7
6.4 Preparation of DMF dispersion for determination of the purity indicator.....	8
7 Optical measurement procedures and conditions	8
8 Data analysis and results interpretations	9
8.1 Data analysis for characterization of SWCNT diameter.....	9
8.2 Data analysis for determination of the purity indicator	9
8.3 Data analysis for characterization of the ratio of metallic SWCNTs.....	9
9 Measurement uncertainties	9
10 Test report	10
Annex A (informative) Case study for derivation of the relation between optical absorption peaks of SWCNTs and their mean diameter	11
Annex B (informative) Case study for determination of the purity indicator	16
Bibliography	19

Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

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Nanotechnologies — Characterization of single-wall carbon nanotubes using ultraviolet-visible-near infrared (UV-Vis-NIR) absorption spectroscopy

1 Scope

This document provides guidelines for the characterization of compounds containing single-wall carbon nanotubes (SWCNTs) by using optical absorption spectroscopy.

The aim of this document is to describe a measurement method to characterize the diameter, the purity, and the ratio of metallic SWCNTs to the total SWCNT content in the sample.

The analysis of the nanotube diameter is applicable for the diameter range from 1 nm to 2 nm.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO/TS 80004-4, *Nanotechnologies — Vocabulary — Part 4: Nanostructured materials*

3 Terms, definitions and abbreviated terms

For the purposes of this document, the terms and definitions given in ISO/TS 80004-4 and the following apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1 Terms and definitions

3.1.1

purity indicator

optically defined indicator of the ratio of the mass fraction of SWCNTs to the total carbonaceous content in a sample

Note 1 to entry: Purity indicator is NOT “purity” itself which is defined as the percentage of mass of SWCNTs to the total mass of the sample. This guideline cannot evaluate this general purity because absorption spectroscopy cannot detect metallic impurities that are generally contained in any SWCNT sample. In order to characterize metal impurity content, there is a different Technical Specification on thermogravimetric analysis. Metallic impurity is defined as catalytic metal particle and does not include metallic carbon nanotube. See ISO TS 11308.

3.1.2

ratio of metallic SWCNTs

optically defined compositional ratio of metallic SWCNTs to the total SWCNTs contained in the sample

3.2 Abbreviated terms

For the purposes of this document, the following abbreviated terms apply.

CMC	Sodium carboxymethylcellulose
DMF	Dimethylformamide
DOS	Density of states
NIR	Near infrared
NMP	N-Methyl-2-Pyrrolidone
SC	Sodium cholate
DOC	Sodium Deoxycholate
SDS	Sodium dodecyl sulfate
SDBS	Sodium dodecylbenzene sulfonate
SWCNT	Single-wall carbon nanotube
TEM	Transmission electron microscope
UV	Ultraviolet
VHS	van Hove singularity
Vis	Visible

4 Principle

4.1 General

All SWCNT samples contain both semiconducting and metallic SWCNTs, together with impurities consisting of carbon and other elements unless the samples have been altered after production. UV-Vis-NIR absorption spectroscopy can be used for the measurement of interband optical transitions specific to SWCNTs. The analysis of these optical transitions provides qualitative and semiquantitative information important for the characterization of SWCNT samples, such as mean diameter, purity, and the ratio of metallic SWCNTs to the total SWCNT content.

4.2 UV-Vis-NIR absorption spectroscopy

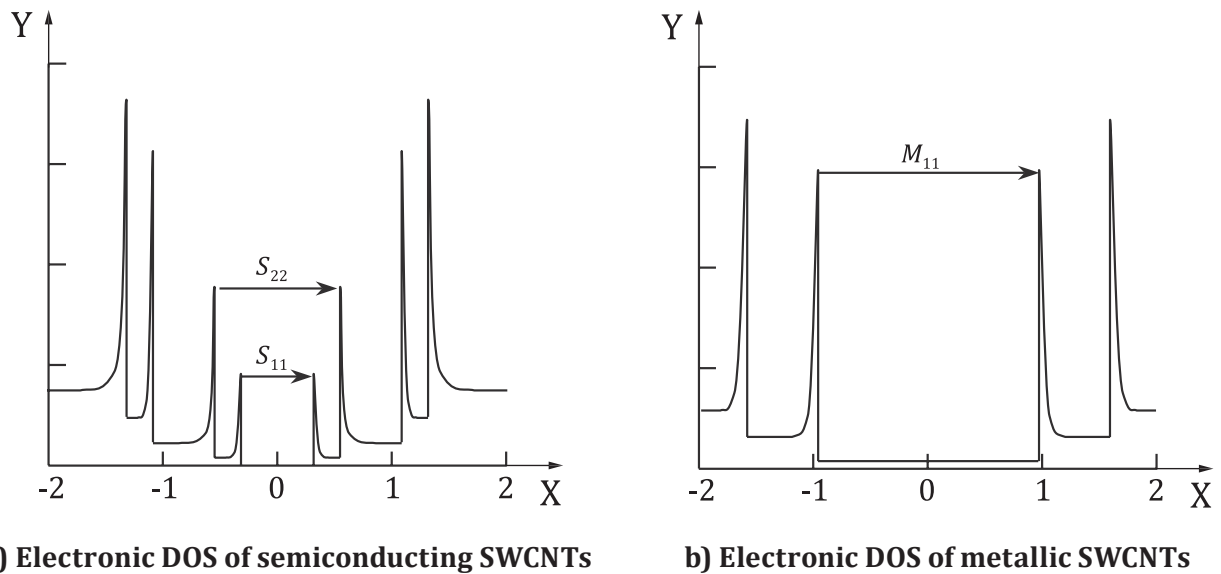
The intensity of light passing at a specified wavelength, λ , through a specimen (I) is measured and it is compared to the intensity of light before it passes through the specimen (I_0). The ratio I/I_0 is called a transmittance. The absorbance, A , is expressed as $-\log(I/I_0)$. The plot of the absorbance against wavelength for a particular compound is referred to as an absorption spectrum.

NOTE The relationship between transmittance and absorbance is only rigorously correct when reflectance is negligible and there is no scattering.

4.3 Optical absorption peaks of SWCNTs in the UV-Vis-NIR region

The shape of the electronic DOS of semiconducting and metallic SWCNTs shown in [Figure 1](#) is a series of spikes that are referred to as VHS. The peaks observed in the optical absorption spectra of SWCNTs are attributed to the electronic transitions between these VHSs as shown by arrows in [Figure 1](#). S_{11} and S_{22} are used as the symbols of the absorption due to the first and second interband transitions of

semiconducting SWCNTs, respectively [see Figure 1 a)]. M_{11} means the absorption arising from the first interband transition of metallic SWCNTs [see Figure 1 b)].



Key

X energy (eV)

Y electronic DOS (arbitrary unit)

S_{11} first interband optical transition attributed to semiconducting SWCNTs

S_{22} second interband optical transition attributed to semiconducting SWCNTs

M_{11} first interband optical transition attributed to metallic SWCNTs

NOTE 1 Arrows represent interband transitions that result in optical absorption.

NOTE 2 See Reference [2].

Figure 1 — Electronic DOS diagram of SWCNTs near the Fermi level

To interpret the absorption spectra of SWCNTs, band structures calculated using the zone-folding method are frequently used. The electronic structure of an SWCNT is generally given by that of a two-dimensional graphite sheet expressed by the tight binding approximation as shown in Formula (1)[2]:

$$E_{2D} = \pm \gamma \left[1 \pm 4 \cos \left(\frac{\sqrt{3}k_x a}{2} \right) \cos \left(\frac{k_y a}{2} \right) + 4 \cos^2 \left(\frac{k_y a}{2} \right) \right]^{1/2} \quad (1)$$

where

E_{2D} is the two dimensional energy dispersion relation for a single graphene sheet;

a is the lattice parameter[3];

k_x and k_y are the components of the reciprocal unit vector;

γ is the overlap integral.